Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/773,158	TANIGUCHI ET AL.	
Examiner	Art Unit	
Hae M. Hyeon	2839	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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439	95		
439	97		
439	98		
439	801	V	1
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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Plus Search Done	4/05	hml		
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